2SC3496, 2SC3496A

Silicon NPN triple diffusion planar type

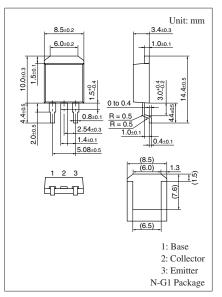
For power switching

Features

- High-speed switching
- \bullet High collector-base voltage (Emitter open) V_{CBO}
- Satisfactory linearity of forward current transfer ratio h_{FE}
- N type package enabling direct soldering of the radiating fin to the printed circuit board, etc. of small electronic equipment

Parameter	Symbol	Rating	Unit		
Collector-base voltage	2SC3496	V _{CBO}	900	V	
(Emitter open)	2SC3496A		1 000		
Collector-emitter voltage	2SC3496	V _{CES}	900	V	
(E-B short)	2SC3496A		1 000		
Collector-emitter voltage	2SC3496	V _{CEO}	800	V	
(Base open)	2SC3496A		900		
Emitter-base voltage (Coll	V _{EBO}	7	V		
Base current	IB	0.3	А		
Collector current	I _C	1	А		
Peak collector current	I _{CP}	2	А		
Collector power	P _C	30	W		
dissipation	$T_a = 25^{\circ}C$		1.3		
Junction temperature		Tj	150	°C	
Storage temperature		T _{stg}	-55 to +150	°C	

Absolute Maximum Ratings $T_C = 25^{\circ}C$



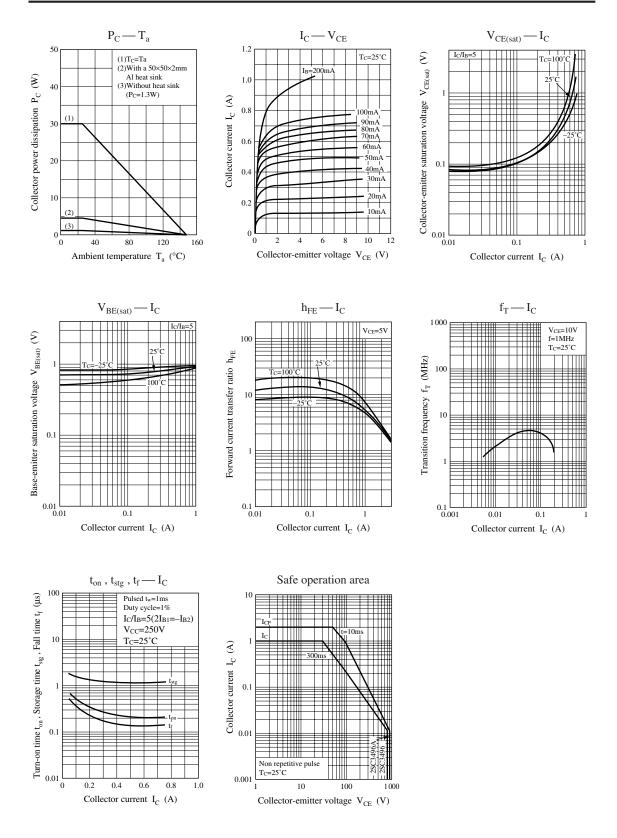
Note) Self-supported type package is also prepared.

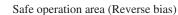
Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

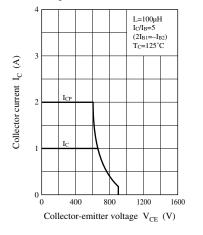
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SC3496	V _{CEO}	$I_{C} = 1 \text{ mA}, I_{B} = 0$	800			V
(Base open)	2SC3496A			900			
Collector-base cutoff current	2SC3496	I _{CBO}	$V_{CB} = 900 \text{ V}, I_E = 0$			50	μΑ
(Emitter open)	2SC3496A		$V_{CB} = 1000$ V, $I_E = 0$			50	
Emitter-base cutoff current (Collector open)		I _{EBO}	$V_{EB} = 7 V, I_C = 0$			50	μΑ
Forward current transfer ratio		h _{FE1}	$V_{CE} = 5 \text{ V}, I_C = 0.05 \text{ A}$	6			
		h _{FE2}	$V_{CE} = 5 V, I_C = 0.5 A$	3			
Collector-emitter saturation	voltage	V _{CE(sat)}	$I_{C} = 0.2 \text{ A}, I_{B} = 0.04 \text{ A}$			1.5	V
Base-emitter saturation volt	age	V _{BE(sat)}	$I_C = 0.2 \text{ A}, I_B = 0.04 \text{ A}$			1.0	V
Transition frequency		f _T	$V_{CE} = 10 \text{ V}, I_C = 0.05 \text{ A}, f = 1 \text{ MHz}$		4		MHz
Turn-on time		t _{on}	$I_{\rm C} = 0.2 {\rm A}$			1.0	μs
Storage time		t _{stg}	$I_{B1} = 0.04 \text{ A}, I_{B2} = -0.08 \text{ A}$			3.0	μs
Fall time		t _f	$V_{CC} = 250 \text{ V}$			1.0	μs

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

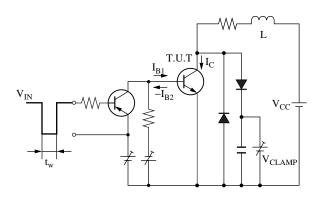
Panasonic

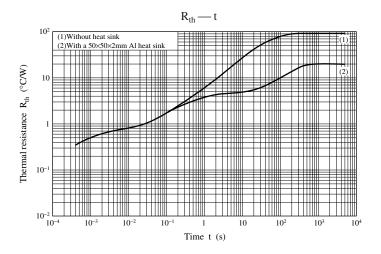






Safe operation area (Reverse bias) measurement circuit





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